Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination OGAWA, HIDEHIKO	
10/767,614		
Examiner	Art Unit	
Thomas D. Lee	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
358	1.15, 402, 440	6/6/2005	TDL		
379	100.01	6/6/2005	TDL		
379	100.08	6/6/2005	TDL		
379	100.13	6/6/2005	TDL		
. 379	100.17	6/6/2005	TDL		
updated		9/14/2005	TDL		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH S	ES STRATEGY	)
	DATE	EXMR
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